CHANGE NOTIFICATION

Analog Devices, Inc.
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June 1, 2017

Dear Sir/Madam: PCN#060117

Subject: **Notification of Change to LTC6811-1, LTC6811-2 Die and Datasheet**

Please be advised that Analog Devices Corporation has made a change to the die of the subject devices to fix conditions that cause an LTC6811-1 or LTC6811-2 device to operate differently than expected or described in the data sheet. These issues are described in the September 2016 LTC6811-1/ LTC6811-2 Product Errata available online at http://www.linear.com/docs/55980.
This new revision of the LTC6811 implements a metal layer mask change to fix these product errata items. In addition, please note that the DRIVE OUTPUT VOLTAGE specification will change in the following manner:

ELECTRICAL CHARACTERISTICS The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T_A = 25°C. The test conditions are V^+ = 39.6V, V_{REG} = 5.0V unless otherwise noted. The ISOMD pin is tied to the V^- pin, unless otherwise noted.

5.7 5.9 5.7 5.7 5.9 6.1 6.1

SYMBOL	PARAMETER	CONDITIONS		MIN	TYP	MAX	UNITS
	DRIVE Output Voltage	Sourcing 1µA		5.4	~~5.6~~	~~5.8~~	V
			●	5.2	~~5.6~~	~~6.0~~	V
		Sourcing 500µA	●	5.1	~~5.6~~	6.1	V
V_{REGD}	Digital Supply Voltage		●	2.7	3	3.6	V
	Discharge Switch ON Resistance	V_{CELL} = 3.6V	●		10	25	Ω
	Thermal Shutdown Temperature				150		°C

The revision BITs in the LTC6811 memory has been changed to identify the LTC6811 revision. Specifically, BIT4 through BIT7 of register STBR5 has been changed from 5 (old revision) to 6 (new revision):

Table 48. Status Register Group B

REGISTER	RD/WR	BIT 7	BIT 6	BIT 5	BIT 4	BIT 3	BIT 2	BIT 1	BIT 0
STBR0	RD	VD[7]	VD[6]	VD[5]	VD[4]	VD[3]	VD[2]	VD[1]	VD[0]
STBR1	RD	VD[15]	VD[14]	VD[13]	VD[12]	VD[11]	VD[10]	VD[9]	VD[8]
STBR2	RD	C4OV	C4UV	C3OV	C3UV	C2OV	C2UV	C1OV	C1UV
STBR3	RD	C8OV	C8UV	C7OV	C7UV	C6OV	C6UV	C5OV	C5UV
STBR4	RD	C12OV	C12UV	C11OV	C11UV	C10OV	C10UV	C9OV	C9UV
STBR5	RD	REV[3]	REV[2]	REV[1]	REV[0]	RSVD	RSVD	MUXFAIL	THSD
		0	1	0	1	Old Revision (5 HEX)			
		0	1	1	0	New Revision (6 HEX)			

The change was qualified by performing characterization over the full operating temperature range and rigorous engineering evaluation across a broad range of application conditions. In addition, the revised die has passed 1000 hours High Temperature Operating Life stress test. Product built using the revised die with new test limits will be shipped with a date code of approximately 1738.

Should you have any further questions, please feel free to contact your local Analog Devices Inc. sales person or you may contact me at 408-432-1900 ext. 2077, or by E-mail JASON.HU@ANALOG.COM.
If I do not hear from you by August 01, 2017, we will consider this change approved by your company.

Sincerely,

Jason Hu
Quality Assurance Engineer